## Search Notes



Consulted Mark Han

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Application/Control No.

Applicant(s)/Patent Under Reexamination

10743436

RICE ET AL.

Examiner

MacNeill, Elizabeth R

Art Unit 3767

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| Notes | Date | Examiner |
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| Class                   | SubClass  | Date                     | Examiner |
|-------------------------|-----------|--------------------------|----------|
| 604                     | 68,72,135 | 7/18/06                  | GRU      |
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